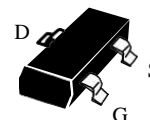


## P-Channel High Density Trench MOSFET

### Features:

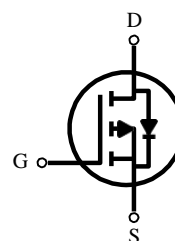
- Super high dense cell trench design for low  $R_{DS(on)}$ .
- Rugged and reliable.
- Surface Mount package.

SOT-23-3L



### PRODUCT SUMMARY

$V_{DSS}$	$I_D$	$R_{DS(on)}$ (m $\Omega$ ) Max
-30V	- 3.7A	70 @ $V_{GS} = -10V$
	- 3.0A	95 @ $V_{GS} = -4.5V$



### ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	$V_{DS}$	- 30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Drain Current-Continuous <sup>a</sup> @ $T_A = 25^\circ\text{C}$ -Pulse <sup>b</sup>	$I_D$	- 3.7	A
	$I_{DM}$	- 14	A
Drain-Source Diode Forward Current <sup>a</sup>	$I_S$	- 1.9	A
Maximum Power Dissipation <sup>a</sup>	$P_D$	$T_A = 25^\circ\text{C}$	1.25
		$T_A = 75^\circ\text{C}$	0.75
Operating Junction and Storage Temperature Range	$T_J, T_{STG}$	- 55 to 150	$^\circ\text{C}$

### THERMAL CHARACTERISTICS

Thermal Resistance, Junction-to-Ambient <sup>a</sup>	$R_{thJA}$	100	$^\circ\text{C/W}$
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Note :

a. Surface Mounted on FR4 Board ,  $t \leq 5\text{sec}$ .

b. Pulse width limited by maximum junction temperature .

ELECTRICAL CHARACTERISTICS (TA = 25 °C unless otherwise noted)

Parameter	Symbol	Condition	Min	Typ <sup>c</sup>	Max	Unit
<b>OFF CHARACTERISTICS</b>						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> = 0V , I <sub>D</sub> = -250uA	-30			V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = -24V , V <sub>GS</sub> = 0V			-1	uA
Gate-Body Leakage	I <sub>GSS</sub>	V <sub>GS</sub> = -20V , V <sub>DS</sub> = 0V			-100	nA
<b>ON CHARACTERISTICS<sup>b</sup></b>						
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250uA	-1	-1.5	-3	V
Drain-Source On-State Resistance	R <sub>DSON</sub>	V <sub>GS</sub> = -10V , I <sub>D</sub> = -3.7A		56	70	mΩ
		V <sub>GS</sub> = -4.5V , I <sub>D</sub> = -3.0A		73	95	
Forward Transconductance	g <sub>fs</sub>	V <sub>DS</sub> = -15V , I <sub>D</sub> = -3.5A		10.2		S
<b>DRAIN-SOURCE DIODE CHARACTERISTICS<sup>b</sup></b>						
Diode Forward Voltage	V <sub>SD</sub>	V <sub>GS</sub> = 0V , I <sub>S</sub> = -1.9A			-1.3	V
<b>DYNAMIC CHARACTERISTICS<sup>c</sup></b>						
Input Capacitance	C <sub>ISS</sub>	V <sub>DS</sub> = -15V , V <sub>GS</sub> = 0V f = 1.0MHz		490		pF
Output Capacitance	C <sub>OSS</sub>			66		pF
Reverse Transfer Capacitance	C <sub>RSS</sub>			53		pF
<b>SWITCHING CHARACTERISTICS<sup>c</sup></b>						
Turn-On Delay Time	t <sub>D(ON)</sub>	V <sub>DD</sub> = -15V , I <sub>D</sub> = -1A		4.4		ns
Rise Time	t <sub>r</sub>		V <sub>GEN</sub> = -10V		2.2	
Turn-Off Delay Time	t <sub>D(OFF)</sub>	R <sub>L</sub> = 15 Ω		22		ns
Fall Time	t <sub>f</sub>	R <sub>GEN</sub> = 6 Ω		4.2		ns
Total Gate Charge	Q <sub>g</sub>	V <sub>DS</sub> = -15V		10		nC
Gate-Source Charge	Q <sub>gs</sub>	I <sub>D</sub> = -1A		1.5		nC
Gate-Drain Charge	Q <sub>gd</sub>	V <sub>GS</sub> = -10V		1.4		nC

Note :

b. Pulse† : Pulse width ≤ 300us , Duty Cycle ≤ 2% .

c. Guaranteed by design , not subject to production testing .

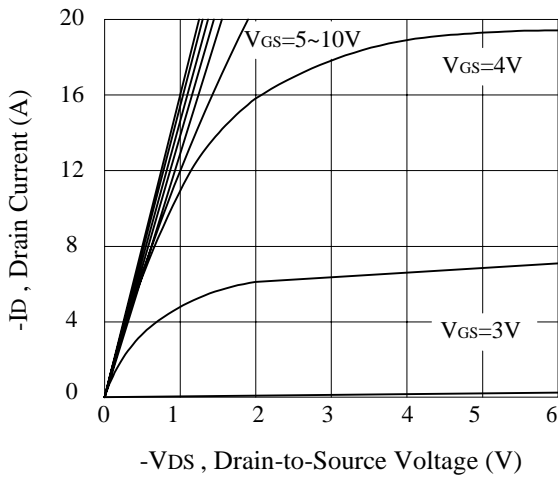


Figure 1. Output Characteristics

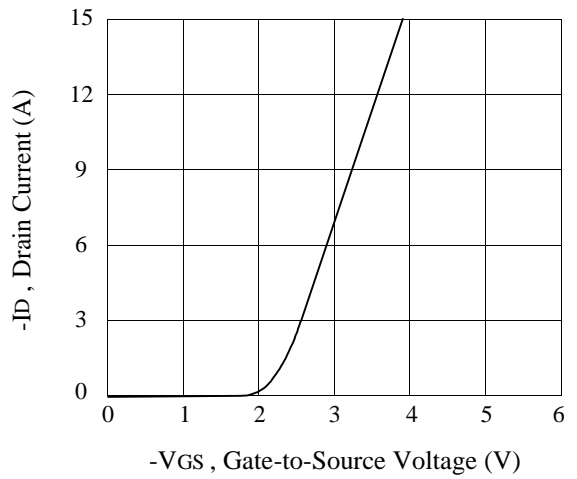


Figure 2. Transfer Characteristics

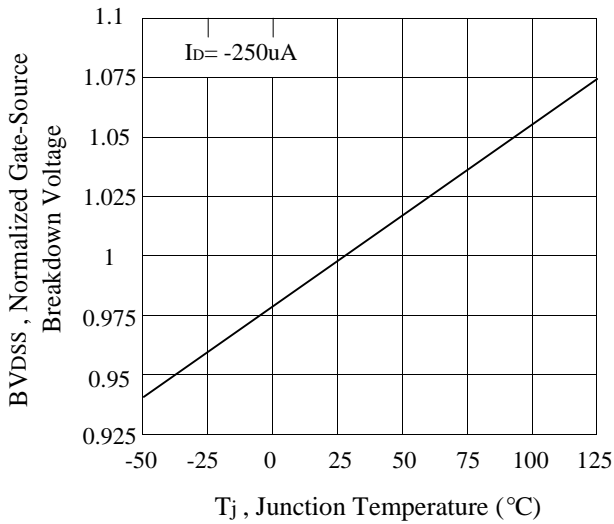


Figure 3. Breakdown Voltage Variation with Temperature

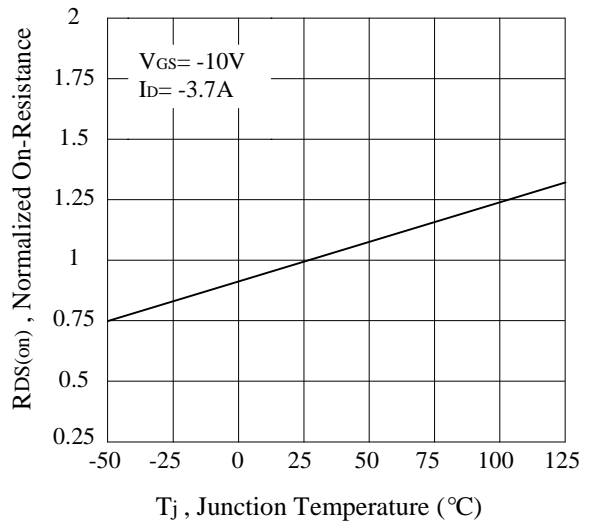


Figure 4. On-Resistance Variation with Temperature

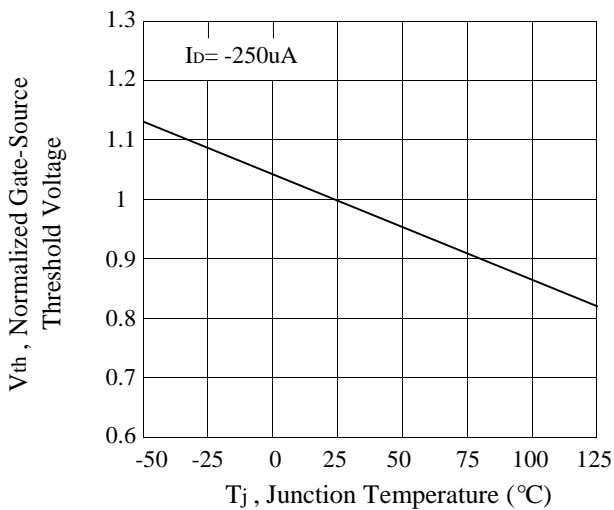


Figure 5. Gate Threshold Variation with Temperature

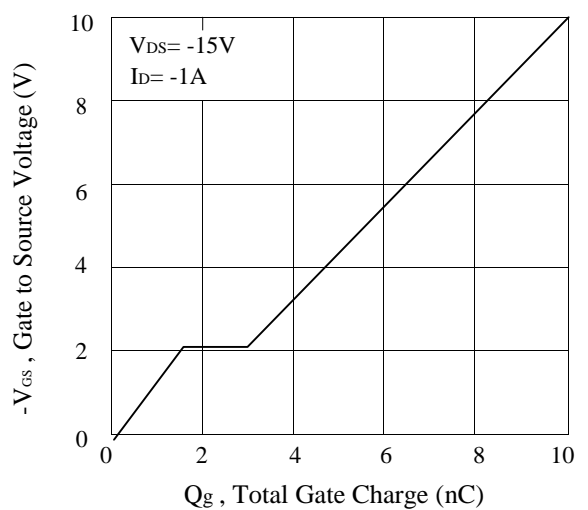
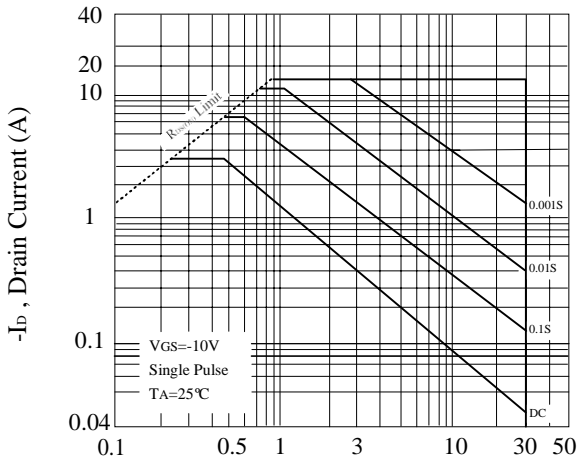
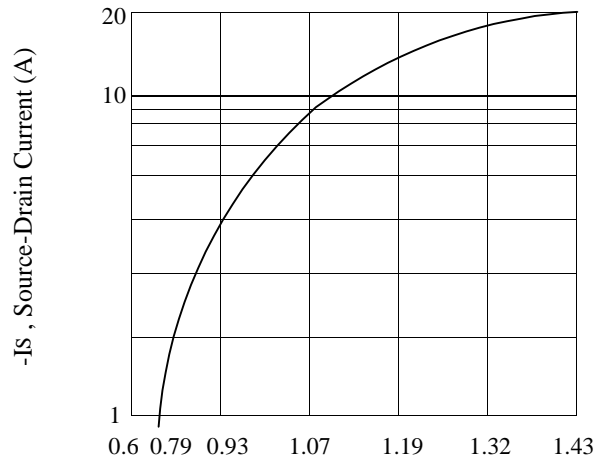


Figure 6. Gate Charge



-VDS, Drain-Source Voltage (V)  
 Figure 7. Maximum Safe Operating Area



-VSD, Body Diode Forward Voltage (V)  
 Figure 1. Body Diode Forward Voltage Variation with Source Current

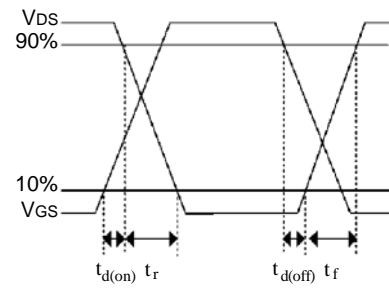
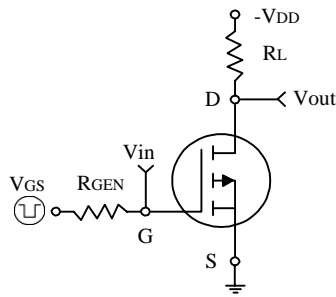


Figure 9. Switching Test Circuit and Switching Waveforms

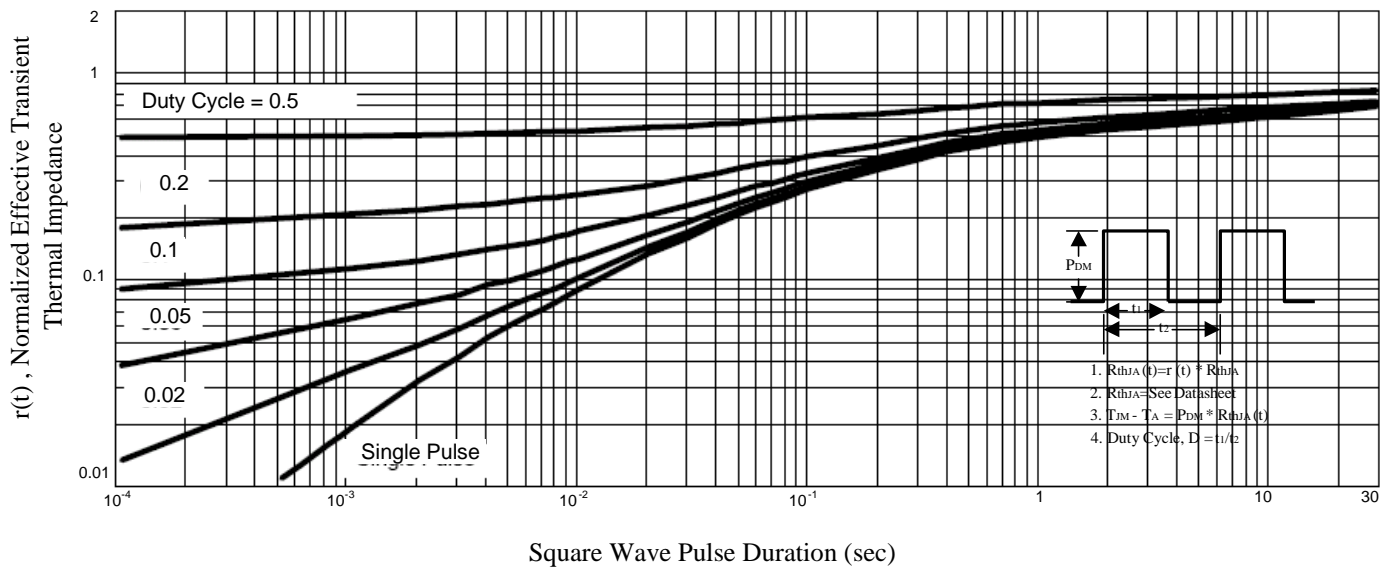


Figure 10. Normalized Thermal Transient Impedance Curve